

<b>Search Notes</b>  <b>*1003517</b>  <b>2*</b>	<b>Application/Control No.</b>  10035172	<b>Applicant(s)/Patent Under Reexamination</b>  HUNTER ET AL.
	<b>Examiner</b>  Hoang-Vu A Nguyen-Ba	<b>Art Unit</b>  2421

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
East Search - USPAT, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB	4/24/07	HAN
East Search - USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	7/23/08 & 7/24/08	HAN
IEEE Search	7/24/08	HAN
Farzana Hossein consulted for possible transfer	2007	HAN
725/32, 36, 22, 40-42, 46, 47, 58, 61 -- text search only	1/19/09	HAN
East Text Search -- USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	8/12/09	HAN
Vu Ngoc consulted	1/5/10	HAN
Joe Ustaris consulted	6/23/10	HAN
EAST text search -- USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	6/25/10	HAN
East Text Search -- USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB	12/18/10	HAN

INTERFERENCE SEARCH			
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